GE Electronic Services	OPERATING PROCEDURE	
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SECTION 1 -- INTRODUCTORY DESCRIPTION

AND PERFORMANCE REQUIREMENTS

1.1 This procedure establishes the methods for testing a IC600BF800 Local I/O Receiver

IC600YB800 Local I/O Receiver

Hereinafter, the unit being tested will be referred to as the UUT (Unit Under Test).

UUT environmental ranges: Temp. 72 degrees +- 5%

RH 20-80 %

UUT warm-up/stabilization period requirements:

none

It is advised that the schematics or operational instructions be available for reference in conjuction with this procedure.

(A copy of the schematic or operating instructions is located in the libary)

Personnel using this procedure are expected to have a high degree of confidence and expertise in related testing and calibration procedures. Procedures not explained here are considered to be understood as common practice.

SECTION 2 -- MEASUREMENT STANDARDS AND EQUIPMENT REQUIREMENTS

2.1 All measurement standards used in this procedure shall be traceable and shall have the accuracy, stability, range and resolution required for the intended use. Unless otherwise specified; the collective uncertainty of the measurement standards shall not exceed 25 percent of the acceptable tolerance for each characteristic being calibrated. All deviations shall be documented.

2.2 Series Six Test System Running Test Software System Information Manual

SECTION 3 -- PRELIMINARY OPERATIONS & THEORY OF OPERATION

3.1 Read the entire testing and calibration procedure before beginning the testing and calibration process.

3.2 Verify accuracy of the standard(s) evidence of recent careful calibration.

3.3 Insure that the calibration environment is within the requirements of the published specifications, if any, for the UUT and the calibration standard(s). If no special conditions are required, the calibration procedure shall take place in an environment controlled to the extent necessary to assure continued measurements of required accuracy, giving due consideration to temperatute, humidity, vibration, cleanliness, and other controllable factors.

When applicable, compensating corrections shall be applied to calibration results obtained in an environment which departs from acceptable conditions.

3.4 Visually inspect the UUT.

3.5 Theory of operation:

This card is used to link Series Six I/O Racks to the Series Six CPU Parallel Buss for Data transfer. This card has a limited Driving Distance of 500 feet is the cards maximum capability.

SECTION 4 -- TESTING AND CALIBRATION PROCESS

4.1 Configure the UUT as an End-of-chain device. See Appendix A.

4.2 Locate CPU # 3 Local Rack 1 and verify the System Operation.

4.3 Turn off power to the Rack and remove the shop test card.

4.4 Install the UUT and power up Test Rack.

4.5 Reset all Downstream Racks and the CPU if necessary.

4.6 Verify that all Downstream I/O tests are running properly.

4.7 Let card run in this configuration for 30 minutes.

4.8 If no failures occur then Power Down the Test Rack and remove the UUT.

4.9 Reinstall the shop test card and Power Up the Test Rack.

4.10 Reset all Downstream I/O Tests and the CPU if

necessary.

4.11 Configure the UUT as an Intermediate Device. See Appendix A.

4.12 Locate CPU #2 Local Rack 1 and verify the System Operation.

4.13 Turn off Power to the Rack and remove the shop test card.

4.14 Install the UUT and Power Up Test Rack.

4.15 Reset all Downstream Racks and the CPU if necessary.

4.16 Verify that all Downstream I/O Tests are Running properly.

4.17 Let card run in this configuration for several hours.

4.18 If no Failures occur then Power Down the Test Rack and remove the UUT.

4.19 Reinstall the shop test card and Power Up the Test Rack.

4.20 Reset all Downstream I/O Tests and the CPU if necessary. (Test complete)

SECTION 5 -- CHECKLIST / DATA SHEET